



Department: Calibration Laboratory ISO/IEC 17025:2005 Accreditation No. 007

Schedule of Accreditation

Name and Address:

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Schedule of Accreditation

Item	Scope Type	Site	Measurand, Instrument, Gauge	Range [Including margins] (Does not include margins)	CMC Expressed as an Expanded Uncertainty (95%)	Reference Document	Remarks
Calibration – Mechanical Quantities - Length					כיול – גדלים מכניים - אורך		
1	A	P	Diameter, Plain Ring Gauges Parallel קוטר, מדיד טבעת חלקה מקביל	[5 mm to 100 mm]	3.0 μm	DIN 2250	SIP measuring machine The uncertainty is claimed for effective diameter,
2	A	P	Diameter, Thread Plug Gauges Parallel קוטר, מדיד הברגה זכר מקביל	[1.5 mm to 100 mm]	3.1 μm	FED-STD-H-28 ISO 1502	SIP measuring machine Measuring wires The uncertainty is claimed for effective diameter
3	A	P	Diameter, Thread Ring Gauges Parallel קוטר, מדיד הברגה טבעת מקביל	[2 mm to 100 mm]	4.0 μm	FED-STD-H-28 ISO 1502	Calibration by check plugs The uncertainty is claimed for effective diameter
4	A	P	Length, Gauge Blocks (by Comparison) אורך, מקבילונים	[0.5 mm to 25 mm]	0.50 μm	ISO 3650	Comparator TESA
5	A	P		(25 mm to 50 mm)	0.60 μm		
6	A	P		(50 mm to 100 mm)	0.70 μm		
7	A	P	Length, Caliper electronic אורך, זחון אלקטרוני	[0.5 mm to 300 mm]	30 μm	DIN 862	Gauge Blocks
8	A	P		(300 mm to 500 mm)	40 μm		
9	A	P		(500 mm to 1500 mm)	70 μm		
10	A	P	Length, Caliper vernier אורך, זחון וורניר	[0.5 mm to 300 mm]	50 μm	DIN 862	Gauge Blocks Resolution 0.05 mm Resolution 0.02 mm
11	A	P		(300 mm to 500 mm)	60 μm		
12	A	P		(500 mm to 1500 mm)	80 μm		
13	A	P	Length, Caliper Depth Gage אורך, זחון לבדיקת עומק	(0 mm to 300 mm)	40 μm	DIN 862	Gauge Blocks
14	A	P	Length, Dial Calibration Tester אורך, כייל חוגנים	(0 mm to 25 mm)	1.6 μm	Manufacturer instructions	Gauge Blocks Comparator TESA

Site: P or T or M, P-Permanent, T-Temporary, M-Mobile

Type of Scopes: A- Fixed, C- Flexible

Flexible scope in analytical tests : Type of matrix, analytes, experimental systems and/or analytical characteristics may be subject to changes, in accordance with the laboratory's approved and documented procedures. For details, please refer to the list of Accredited Tests, available from the laboratory upon request.

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The certificate attached is an integral part of the schedule and is numbered identically התעודה המצורפת לנספח זה מהווה חלק בלתי נפרד ממנו ומספרה זהה למספר הנספח

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15	A	P	Length, אורך, חוגן מנופי	(0 mm to 0.2 mm)	2.1 µm	BS 2795	Resolution 0.001 mm
16	A	P	Dial Gauge, Lever	(0 mm to 0.8 mm)	6.1 µm		Resolution 0.01 mm Indicator Tester
17	A	P	Length, אורך, חוגן	(0 mm to 1.0 mm)	2.0 µm	DIN 878	Indicator Tester
18	A	P	Dial Indicator	(1 mm to 50 mm)	7.3 µm		
19	A	P	Length, אורך, מוטות כיול למיקרומטר	[15 mm to 25 mm]	1.0 µm	BS 870	SIP measuring machine
20	A	P	Micrometer Extension	(25 mm to 100mm)	1.1 µm		Gauge Blocks
21	A	P	Rod	(100 mm to 200 mm)	1.9 µm		
22	A	P		(200 mm to 300 mm)	2.5 µm		
23	A	P		(300 mm to 400 mm)	3.8 µm		
24	A	P		(400 mm to 500 mm)	5.0 µm		
25	A	P	Length, אורך, מיקרומטר חיצוני	(0 mm to 100 mm)	2.5 µm	DIN 863/1	Gauge Blocks
26	A	P	Micrometer External	(100 mm to 200 mm)	3.4 µm		
27	A	P		(200 mm to 300 mm)	4.6 µm		
28	A	P		(300 mm to 400 mm)	5.8 µm		
29	A	P		(400 mm to 500 mm)	6.6 µm		
30	A	P	Length, אורך, מיקרומטר עומק	(0 mm to 50 mm)	3.4 µm	JIS B 7544	Gauge Blocks
31	A	P	Micrometer Depth	(50 mm to 100 mm)	4.4 µm		
32	A	P		(100 mm to 200 mm)	5.1 µm		

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33	A	P		(200 mm to 300 mm)	5.5 μm		
34	A	P	Length, אורך,	[4 mm to 50 mm]	3.5 μm	DIN 863/4	Plain Ring Gauge
35	A	P	Micrometer Inside 3 נקודות מיקרומטר פנימי 3 Points	(50 mm to 100 mm)	5.1 μm		
36	A	P	Length, אורך,	[10 mm to 100 mm]	4.8 μm	DIN 863/4	Plain Ring Gauges
37	A	P	Micrometer Inside 2 נקודות מיקרומטר פנימי 2 Points	(100 mm to 200 mm)	6.1 μm		SIP measuring machine
38	A	P		(200 mm to 300 mm)	6.6 μm		
39	A	P	Length, Thread Measuring Wires אורך, תלילים למדידת הברגה	[0.17 mm to 3.2 mm]	0.95 μm	FED-STD H-28	SIP measuring machine
40	A	P	Length, Bore Gauge אורך, מד קטרים	[1 mm to 150 mm]	3.1 μm	JIS- B 7515	Dial Calibration Tester SIP measuring machine Comparator TESA
41	A	P, T	Length, אורך,	(0 mm to 300 mm)	8.8 μm	JIS-B-7517	Resolution 0.01 mm
42	A	P, T	Height Gauge מד גובה	(0 mm to 600 mm)	16 μm		Resolution 0.01 mm
43	A	P, T		(0 mm to 600 mm)	4.6 μm		Resolution 0.001 mm Gauge blocks
44	A	P, T	Length, Profile Projector אורך, פרופילרים מטול	(0 mm to 200 mm)	3.6 μm	JIS-B-7814	Optical bar Angel Block
45	A	P	Length, Pin Gauge אורך, פינים מדויקים	[0.22 mm to 25 mm]	1.5 μm	Manufacturer instructions	MITUTOYO measuring machine
46	A	P	Length, אורך,	(0 mm to 100 mm)	0.9 μm	Manufacturer instructions	Gauge Blocks
47	A	P	Length Measuring מכונה למדידת אורך	(100 mm to 200 mm)	1.5 μm		

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Calibration – Mechanical Quantities - Length					כיול – גדלים מכניים - אורך		
48	A	P	Machine	(200 mm to 300 mm)	2.0 μm		
49	A	P	Length, Feeler Gauge	אורך, מד רווח [0.04 mm to 3.0 mm]	3.1 μm	JIS-B-7524	MITUTOYO measuring machine
50	A	P	Length. Gauge Block Comparator	אורך קומפראטור לכיול מקבלנים [0.5 mm to 100 mm]	0.36 μm	EURAMET cg-2	Gauge Blocks, Comparator TESA

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Calibration – Mechanical Quantities – Form, Angle					כיול – גדלים מכניים – צורה, זווית		
51	A	P	Angle. Bevel Protractor	זווית, מד זווית 360°	4'	GGG-P-676	Angel Block
52	A	P	Form. Straightness. "V" Block	צורה, ישרות, בלוק "V" Up to 50 mm]	3.6 μm	JIS-B-7540	Gauge Blocks Comparator TESA Sine Bar
53	A	P, T	Form, Flatness, Granite Surface Plates	צורה, שטיחות, לוחות שטוחים גרניט Up to 3 m]	5.7 μm	GGG-P-463	Digital level meter

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Calibration – Physical Quantities - Force, Torque					כיול – גדלים פיזיקליים - כח, מומנט		
54	A	P	Torque, Torque Wrenches	מומנט, מפתחות מומנט	[2 Nm to 1000 Nm]	3.3 %	ISO 6789 2003 STAHLWILLE Torque Calibrator

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Calibration – Physical Quantities - Pressure					כיול – גדלים פיזיקליים - לחץ		
55	A	P	Pressure, Pneumatic, Gauge Pressure, Pressure Gauges	לחץ, פניאומטי, לחץ יחסי, מדידי לחץ	[0.1 MPa to 2 MPa] (2 MPa to 10 MPa)	5 Pa/kPa 2 Pa/kPa	OIML R 101 1991 DRUCK Pressure calibrator Mechanical and electronic gauges may be calibrated
56	A	P	Pressure, Hydraulic, Pressure Gauges	לחץ, הידראולי, מדידי לחץ	[2 MPa to 10 MPa] (10 MPa to 40 MPa) (40 MPa to 60 MPa) (60 MPa to 100 MPa)	4.3 Pa/kPa 1.5 Pa/kPa 5.3 Pa/kPa 8 Pa/kPa	

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Calibration – Physical Quantities - Temperature					כיוול – גדלים פיזיקליים - טמפרטורה		
57	A	P, T	Temperature, Digital thermometers with sensors: platinum resistance, thermistor, thermocouple	טמפרטורה, מדי טמפרטורה דיגיטליים עם רגשים: התנגדות פלטינה, תרמיסטור, צמד תרמי	(0 °C to 100 °C] (100 °C to 300°C] (300 °C to 500 °C]	0.8 °C 2.1 °C 3.5 °C	ASTM E2877 - 12e1 Manufacturer Instructions Ametek Temperature Calibrator
58	A	P, T	Temperature, Controllers of Furnaces and Freezers	טמפרטורה, בקרים של תנורים וממקפיאים,	(-20 °C to 70 °C] (70 °C to 200 °C] (200 °C to 500 °C]	1.1 °C 1.5 °C 4.0 °C	DKD-R 5-7: 2004, in concern to controllers Manufacturer Instructions TESTO 174 Fourier Data Logger

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